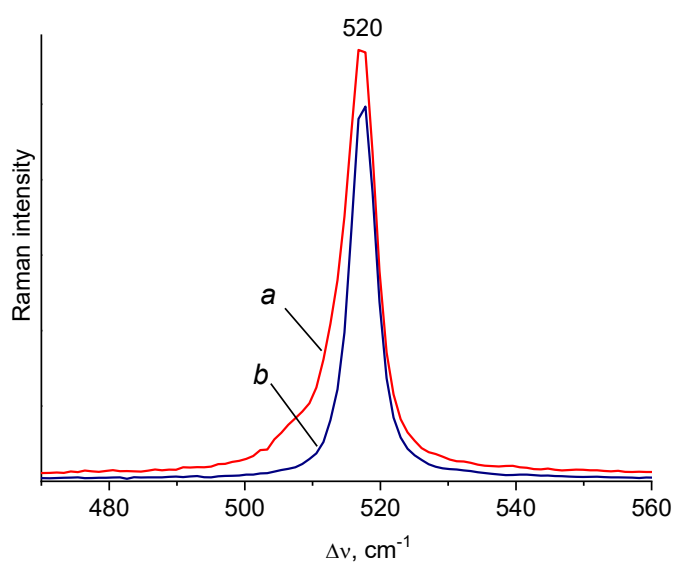


## Electronic supplementary information

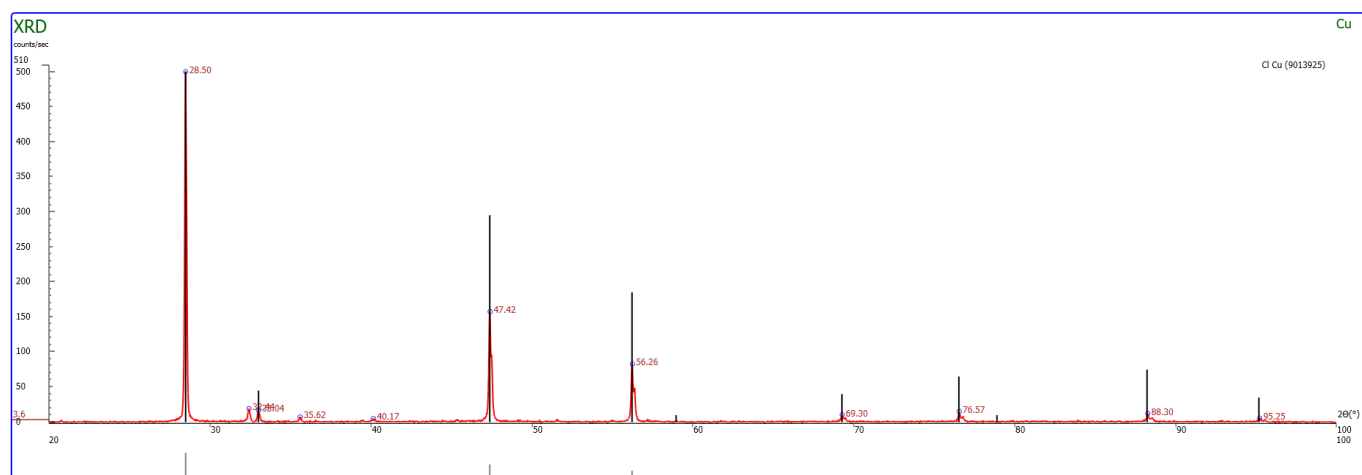
### CONTACT MASS IN THE DIRECT SYNTHESIS OF ALKOXYSILANES. RAMAN SPECTROSCOPY STUDY

S. S. Bukalov, M. N. Temnikov, I. N. Krizhanovskiy, and R. R. Aysin\*

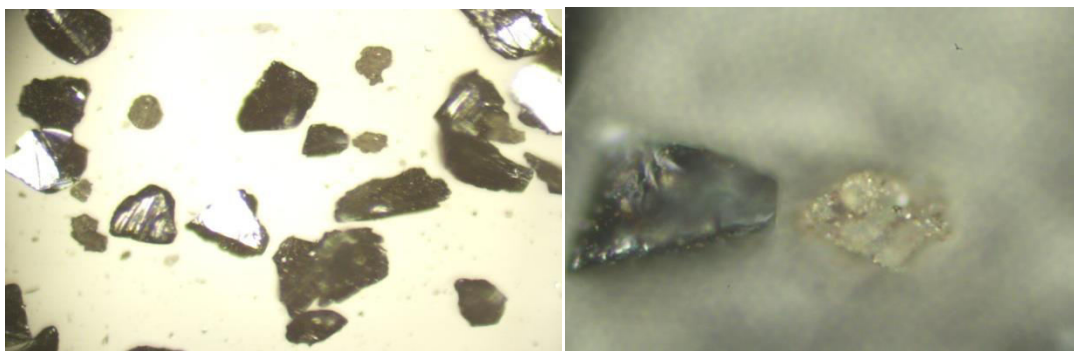
*Nesmeyanov Institute of Organoelement Compounds, Russian Academy of Sciences,  
ul. Vavilova 28, str. 1, Moscow, 119334 Russia*



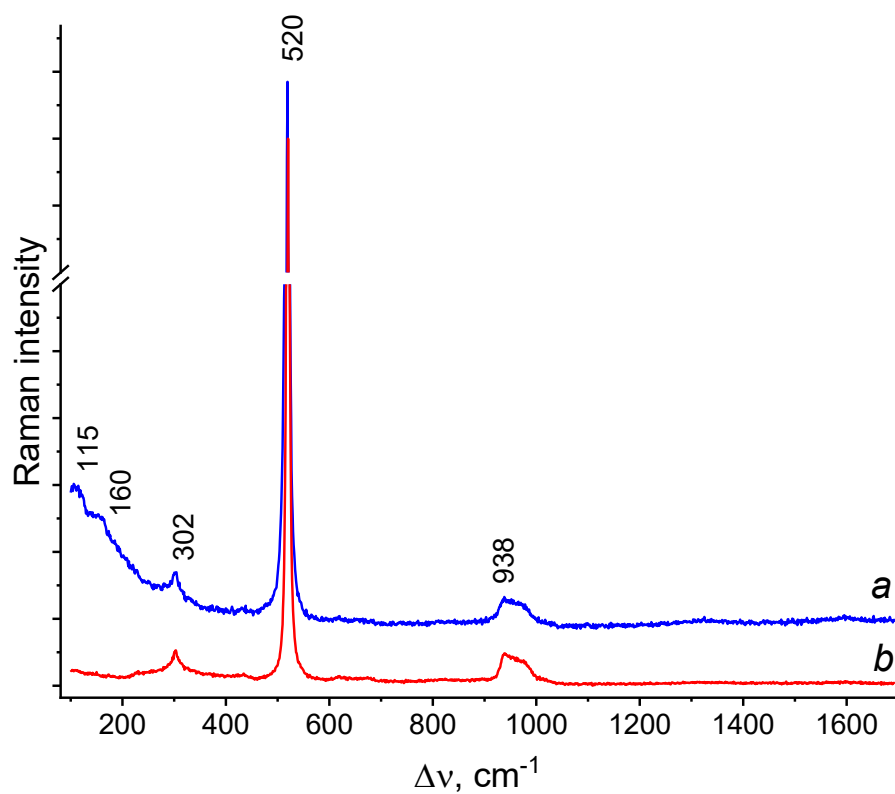
**Fig. S1.** Raman spectra in the TO mode region for technical silicon (*a*) and monocrystalline metallic Si wafer (*b*).



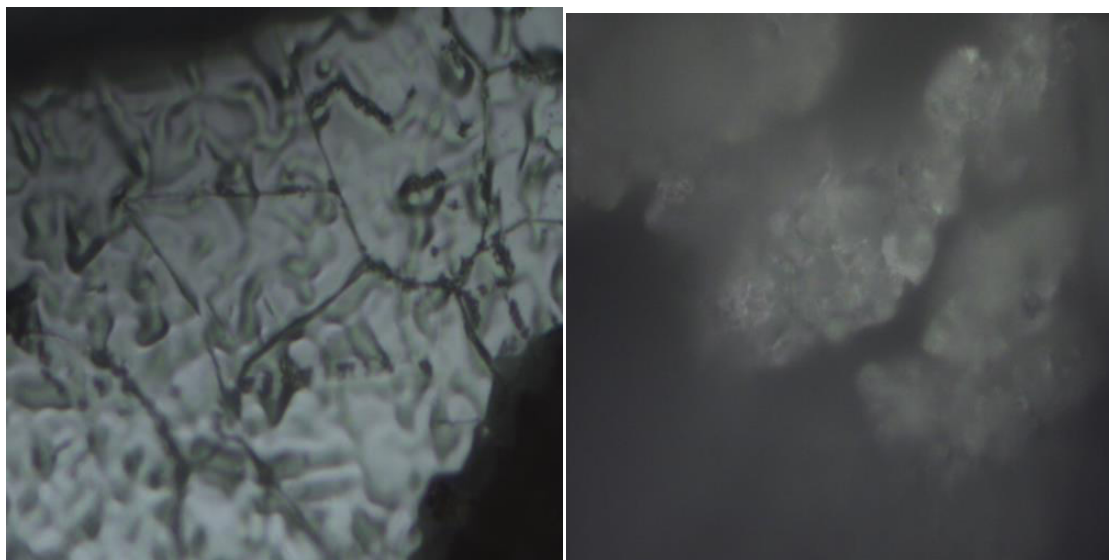
**Fig. S2.** XRD pattern for CuCl (97%, Sigma-Aldrich).



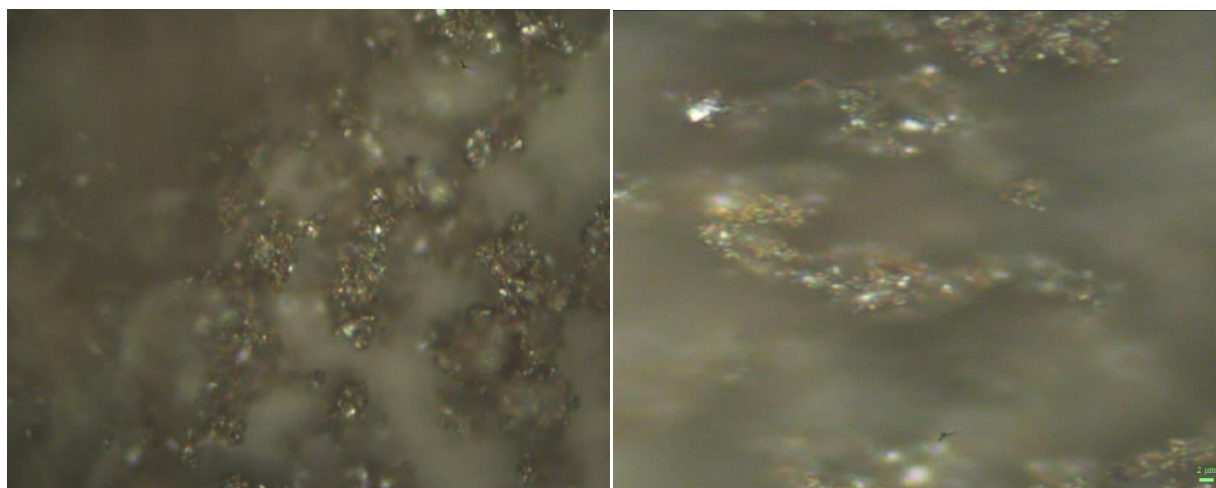
**Fig. S3.** Microphotographs for **CM1a** particles under 10× (*left*) and 50× (*right*) magnification.



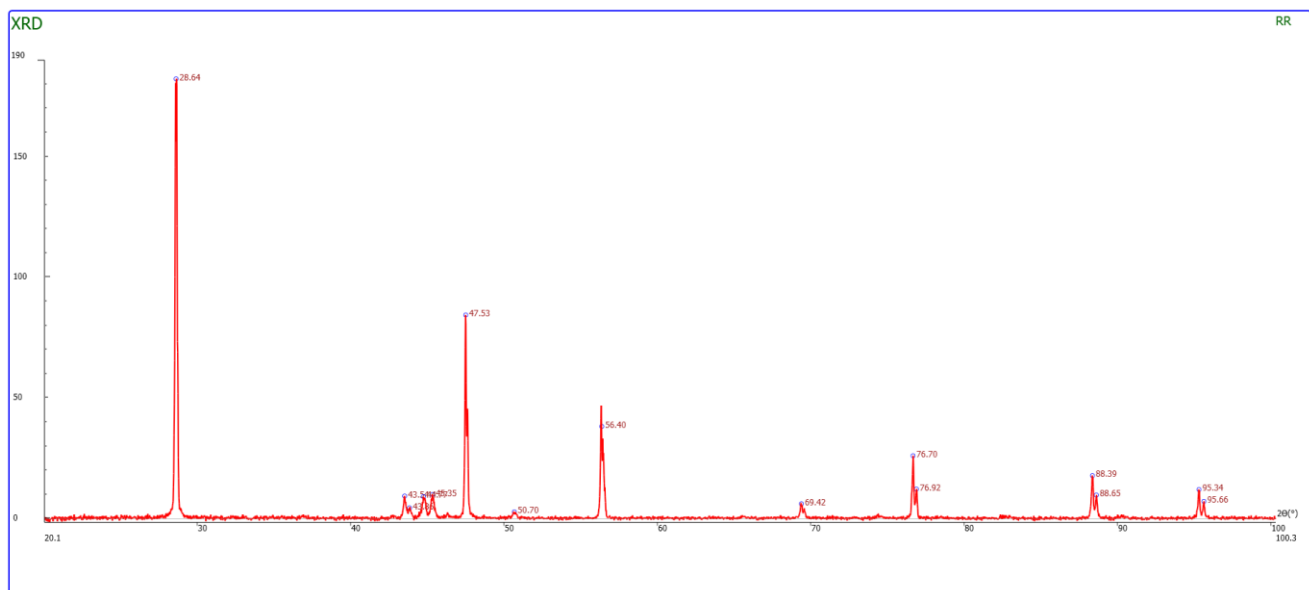
**Fig. S4.** Raman spectra for the light (*a*) and dark (*b*) particles presented in Fig. S3.



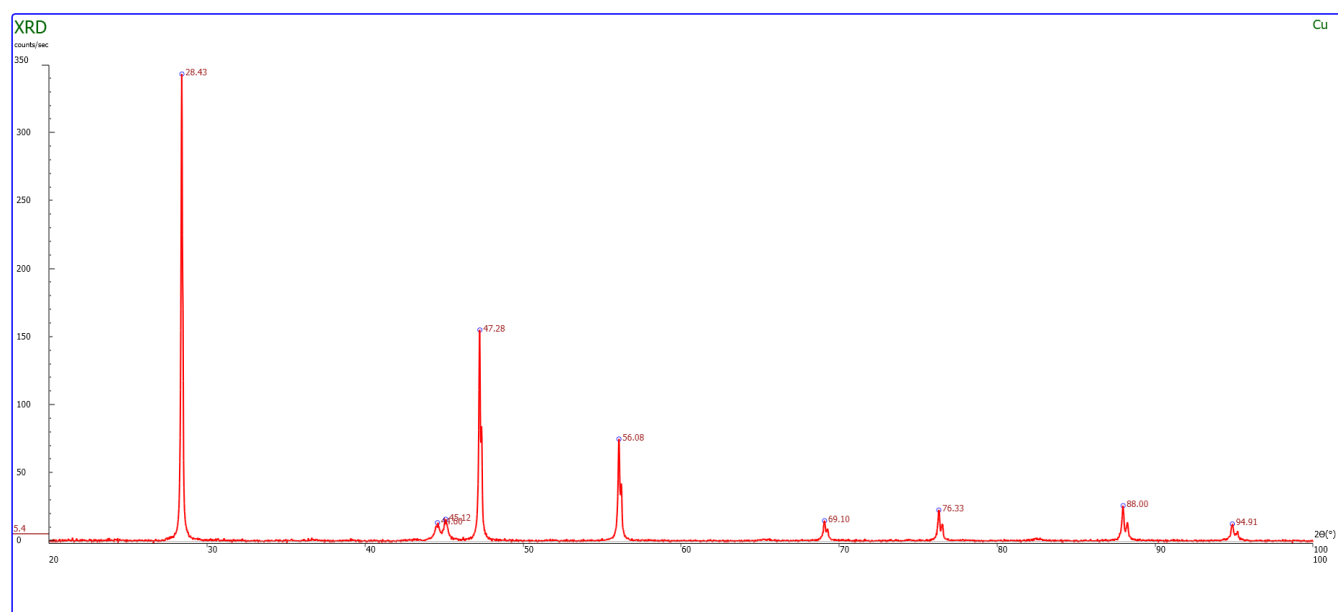
**Fig. S5.** Surface of the CuCl film of sample **CM4a** (*left*) and purified CuCl (*right*) under 50× magnification.



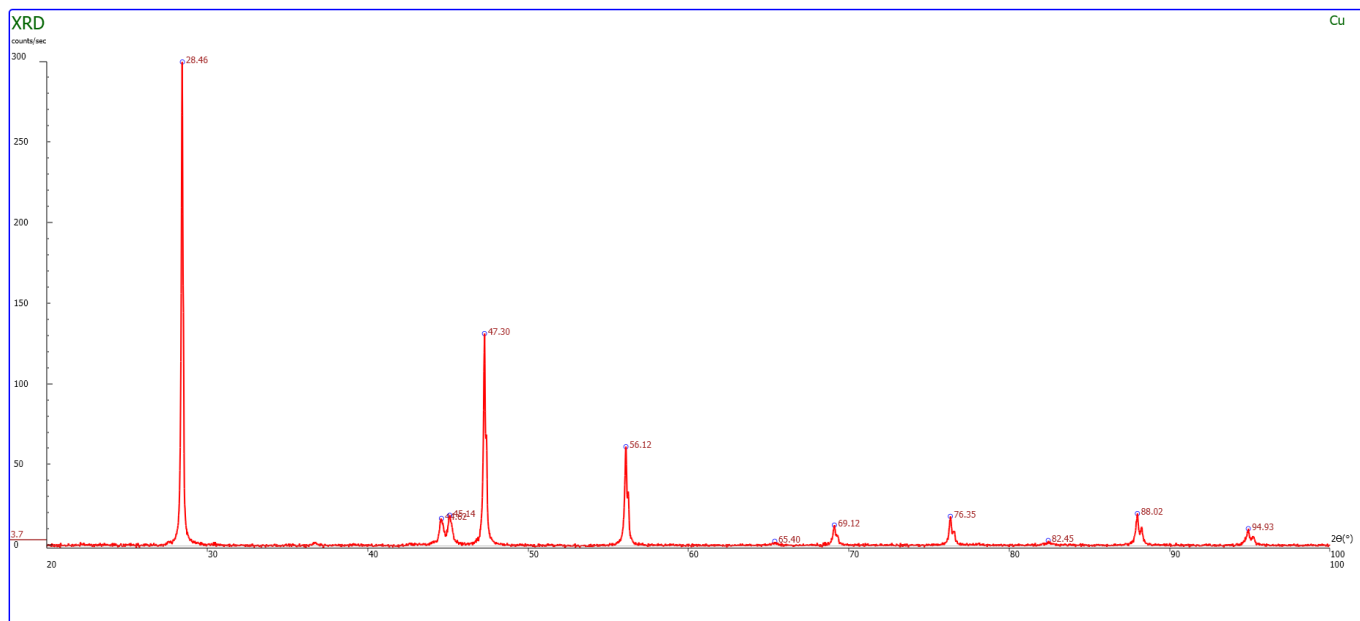
**Fig. S6.** Microphotographs for samples **CM2** (*left*) and **CM3** (*right*).



**Fig. S7.** XRD pattern for sample CM1.



**Fig. S8.** XRD pattern for sample CM2.



**Fig. S9.** XRD pattern for sample CM3.